

AMAT UVision 200S Serial nr T730 Vintage 2007 300mm

Information contained in this presentation is confidential

AMAT UVision 200S Serial nr T730 Vintage 2007 300mm Location warehouse Nijmegen condition "As is"

Manufacturer: Applied Materials Type: 300mm UVision Serial number: T730 Date of manufacture: 2007

The AMAT

Uvision SP 200 is a BF (Bright Field) wafer inspection tool It is designed to inspect pattern wafers, but it can also inspect bare and unpatterned wafers Ligth source: Laser (266 = anm) Tool scans a wafer in a meander path Die to Die " and Cell to Cell " comparison capability Can use reflected --(BrigthField) and scattered signal (GF = GreyField) in parallel for detection On pattern wafers capable of detecting defects of 25 nm with 90 % Capture Rate (Data from D&E recipe,







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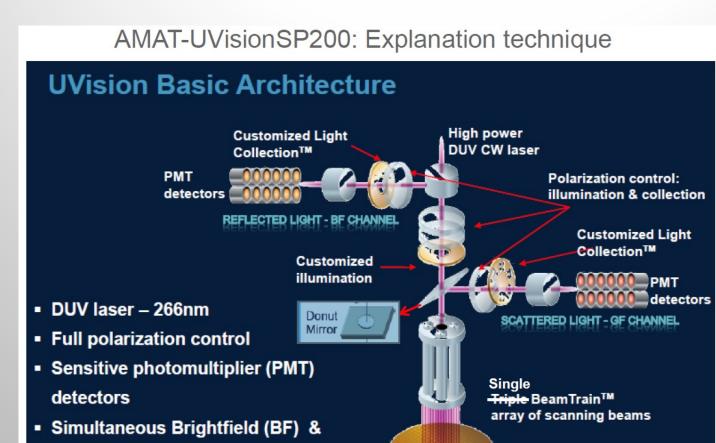


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scattered light – Greyfield (GF)

inspection





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